

<b>Search Notes</b> 	<b>Application/Control No.</b> 10/817,412	<b>Applicant(s)/Patent under Reexamination</b> RYKEN ET AL.
	<b>Examiner</b> Shih-Chao Chen	<b>Art Unit</b> 2821

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
343	700MS	6/30/2005	CHEN
343	846, 853	6/30/2005	CHEN